

# INTERNATIONAL STANDARD

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## Semiconductor devices – Part 5-5: Optoelectronic devices – Photocouplers





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This second edition cancels and replaces the first edition published in 2007 and Amendment 1:2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) optional data sheet basic insulation rating in accordance with IEC 60664-1:2007, 6.1.3.5;
- b) editorial corrections on the use of  $V_{IORM}$ ;
- c) editorial corrections on Figure 2: Time intervals for method b);
- d) addition of an alternative surge pulse  $V_{IOSM}$  test method.

The text of this International Standard is based on the following documents:

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47E/706/FDIS	47E/714/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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